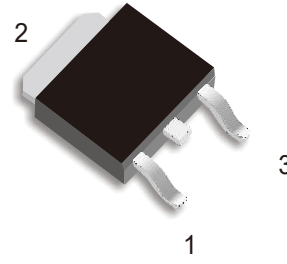
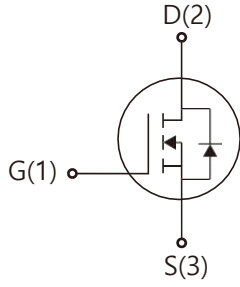


<p>CTKD10N65SE</p> <p>Features:</p> <ul style="list-style-type: none"> <input type="checkbox"/> Low Intrinsic Capacitances. <input type="checkbox"/> Excellent Switching Characteristics. <input type="checkbox"/> Extended Safe Operating Area. <input type="checkbox"/> Unrivalled Gate Charge :Qg=35nC (Typ.). <input type="checkbox"/> $V_{DSS}= 650V, I_D=10A$ <input type="checkbox"/> $R_{DS(on)} : 0.9 \Omega$ (Max) @$V_G=10V$ <input type="checkbox"/> 100% Avalanche Tested 	<p style="text-align: center;">TO-252</p> <div style="text-align: center;">  </div> <div style="text-align: center;">  </div> <div style="margin-top: 10px;"> <p>1.Gate (G)</p> <p>2.Drain (D)</p> <p>3.Source (S)</p> </div>
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Absolute Maximum Ratings (Ta=25°C unless otherwise noted)

Sy mbol	Parameter	Value	Unit
V_{DSS}	Drain-Source Voltage	650	V
I_D	Drain Current	$T_j=25^\circ C$	10
		$T_j=100^\circ C$	6.7
V_{GSS}	Gate-Source Voltage	± 30	V
E_{AS}	Single Pulse Avalanche Energy (note1)	380	mJ
I_{AR}	Avalanche Current (note2)	10	A
P_D	Power Dissipation ($T_j=25^\circ C$)	45	W
T_j	Junction Temperature(Max)	150	°C
T_{stg}	Storage Temperature	-55~+150	°C
TL	Maximum lead temperature for soldering purpose,1/8' from case for 5 seconds	300	°C

Thermal Characteristics

Sy mbol	Parameter	Typ.	Max.	Unit
$R_{\theta JC}$	Thermal Resistance,Junction to Case	-	2.4	°C/W
$R_{\theta JA}$	Thermal Resistance,Junction to Ambient	-	62.5	°C/W

Electrical Characteristics (Ta=25°C unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu A, V_{GS}=0$	650	-	-	V
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D=250\mu A$, Reference to 25°C	-	0.67	-	V/°C
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=650V, V_{GS}=0V$	-	-	10	μA
		$V_{DS}=520V, T_J=125^\circ C$	-	-	100	
I_{GSSF}	Gate-body leakage Current, Forward	$V_{GS}=+30V, V_{DS}=0V$	-	-	100	nA
I_{GSSR}	Gate-body leakage Current, Reverse	$V_{GS}=-30V, V_{DS}=0V$	-	-	-100	
On Characteristics						
$V_{GS(TH)}$	Gate Threshold Voltage	$I_D=250\mu A, V_{DS}=V_{GS}$	2	-	4	V
$R_{DS(ON)}$	Static Drain-Source On-Resistance	$I_D=5.0A, V_{GS}=10V$	-	0.8	0.9	Ω
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS}=25V, V_{GS}=0, f=1.0MHz$	-	1500	-	μF
C_{oss}	Output Capacitance		-	194	-	
C_{rss}	Reverse Transfer Capacitance		-	18	-	
Switching Characteristics						
$T_d(on)$	Turn-On Delay Time	$V_{DD}=325V, I_D=10A, R_G=25\Omega$ (Note 3,4)	-	23	-	nS
T_r	Turn-On Rise Time		-	15	-	
$T_d(off)$	Turn-Off Delay Time		-	90	-	
T_f	Turn-Off Rise Time		-	30	-	
Q_g	Total Gate Charge	$V_{DS}=520V, V_{GS}=10V, I_D=10A$ (Note3,4)	-	35	-	nC
Q_{gs}	Gate-Source Charge		-	7	-	
Q_{gd}	Gate-Drain Charge		-	18	-	
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Max. Diode Forward Current	-	-	-	10	A
I_{SM}	Max. Pulsed Forward Current	-	-	-	40	
V_{SD}	Diode Forward Voltage	$I_D=10A$	-	-	1.4	V
T_{rr}	Reverse Recovery Time	$I_S=10A, V_{GS}=0V, diF/dt=100A/\mu s$ (Note3)	-	320	-	nS
Q_{rr}	Reverse Recovery Charge	(Note3)	-	4.2	-	μC

 Notes : 1, L=0.5mH, IAS= 10A, VDD=50V, RG=25 Ω , Starting T_J =25°C

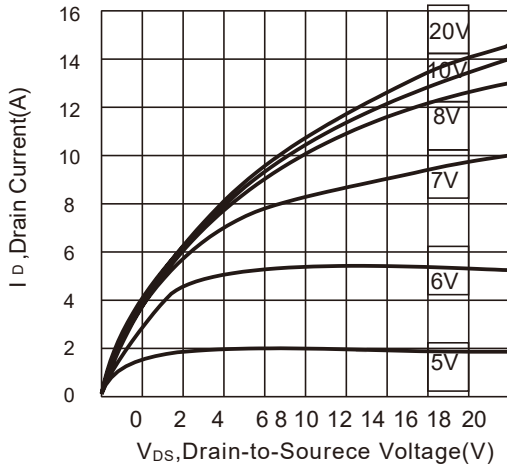
2, Repetitive Rating : Pulse width limited by maximum junction temperature

 3, Pulse Test : Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 2\%$

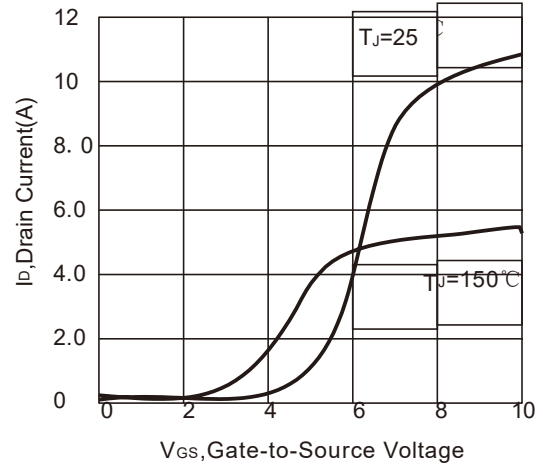
4, Essentially Independent of Operating Temperature

Typical Characteristics

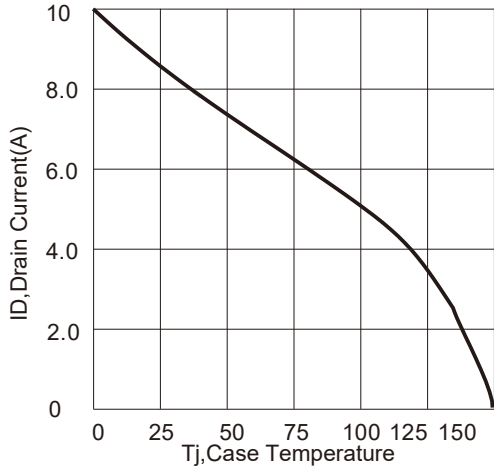
Output Characteristics



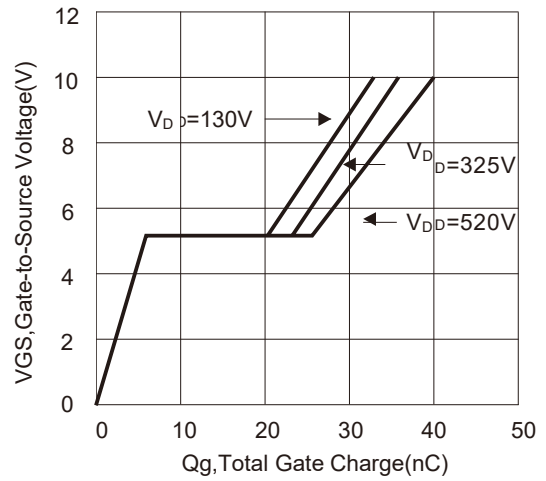
Transfer Characteristics



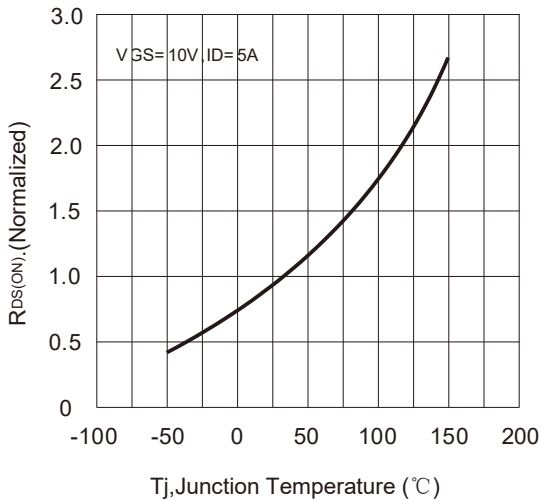
Drain Current VS. Temperature



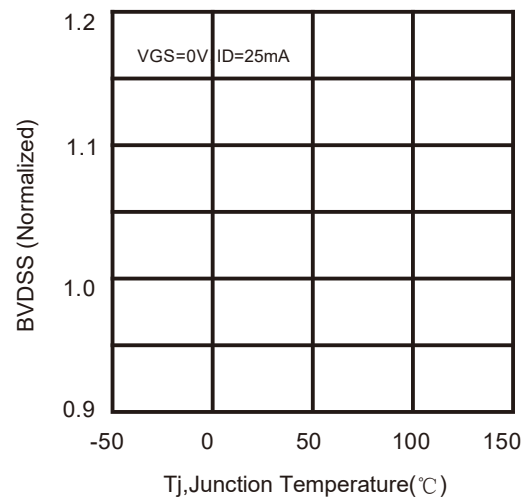
Gate Charge



On-Resistance vs. Junction Temperature

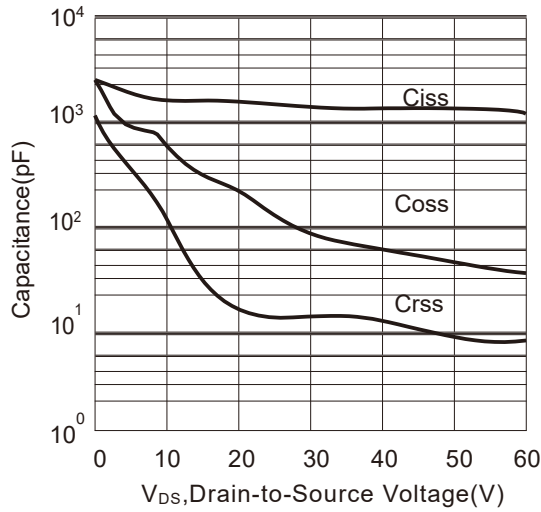


BVDS Variation VS. Temperature

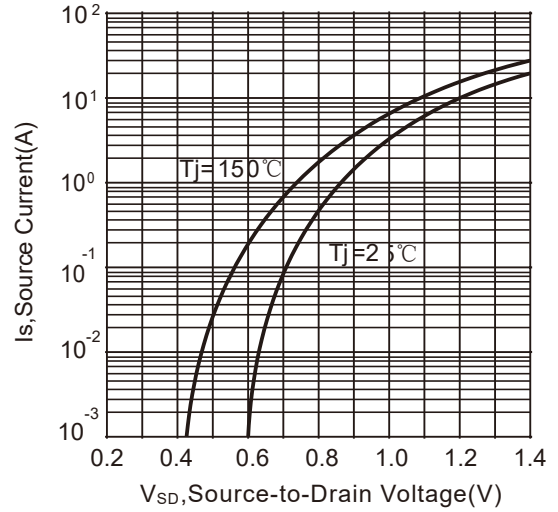


Typical Characteristics (Continued)

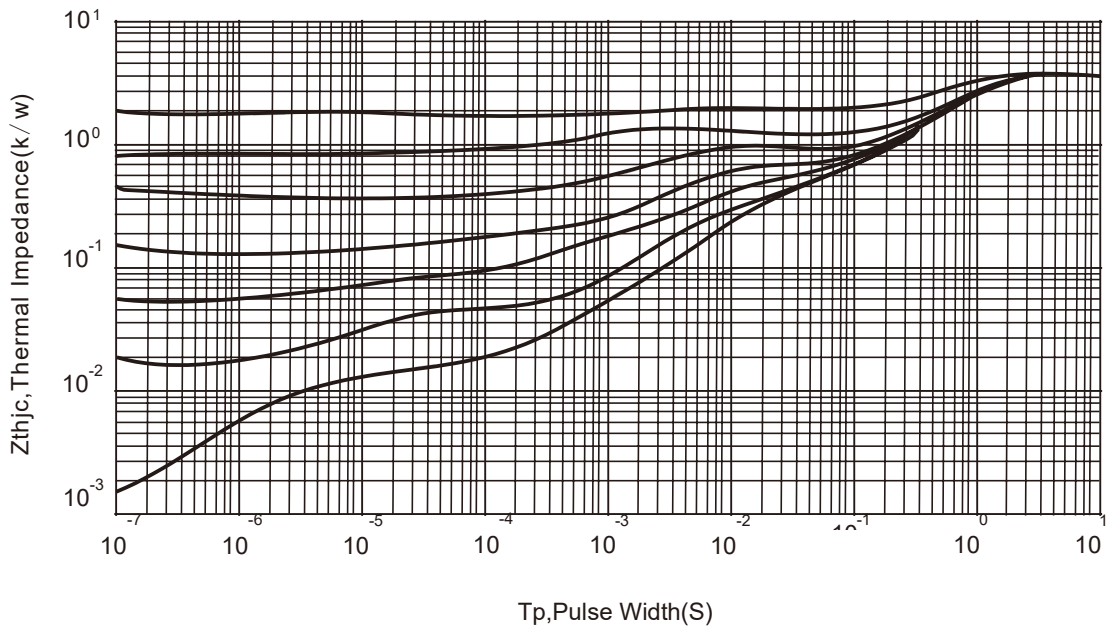
Capacitance



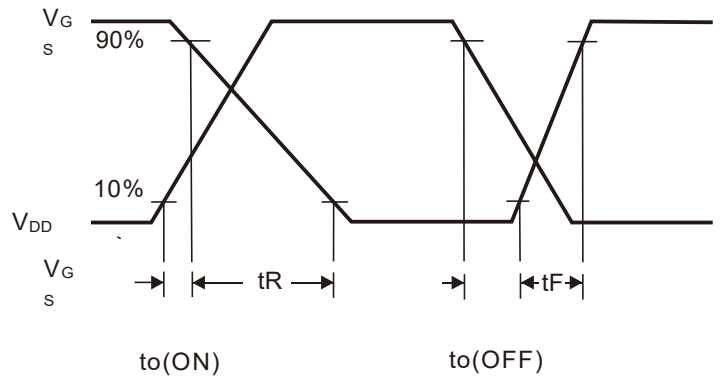
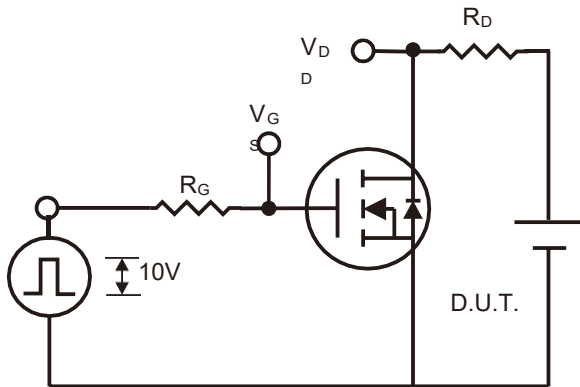
Body Diode Forward Voltage



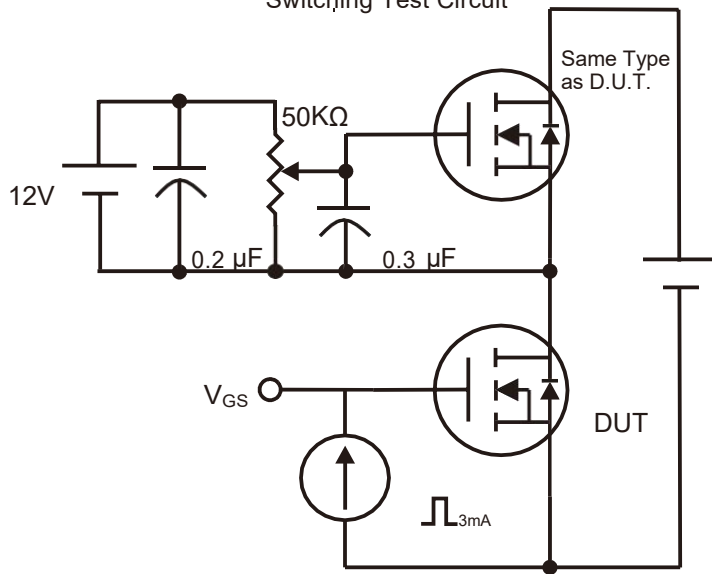
Transient Thermal Impedance



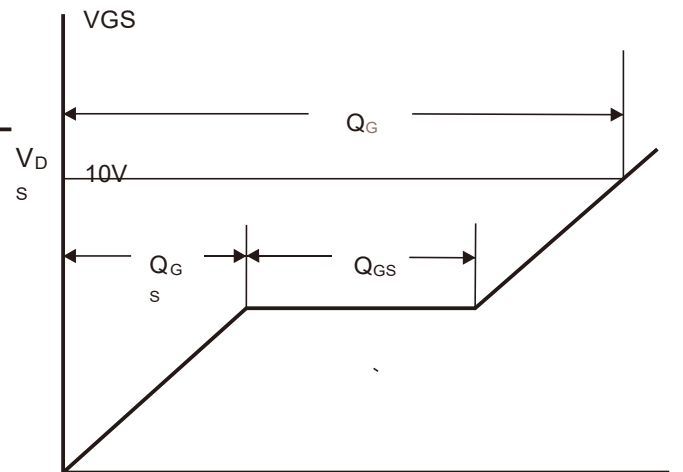
Gate Charge Test Circuit & Waveform



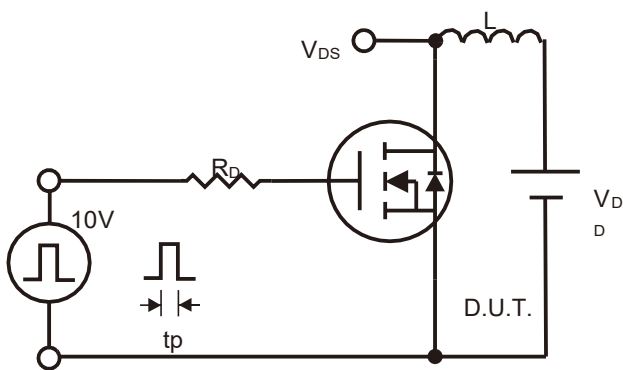
Switching Test Circuit



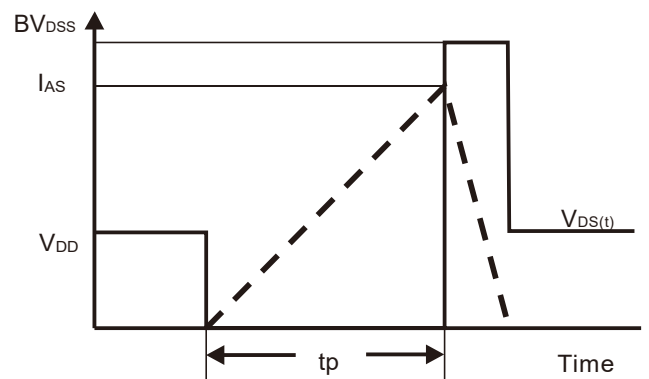
Switching Waveforms



Gate Charge Test Circuit



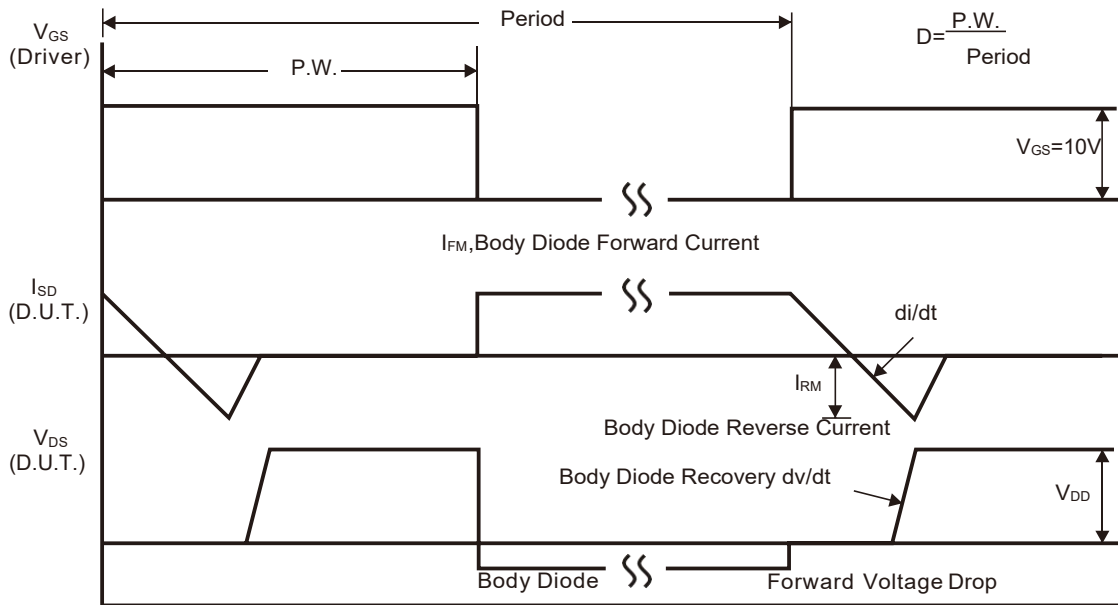
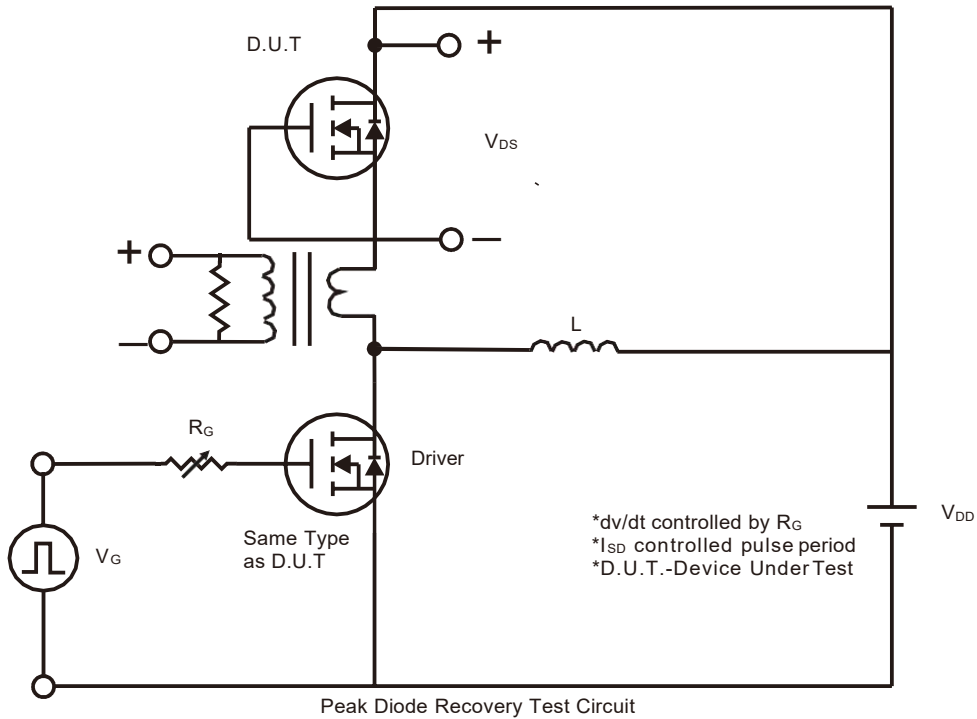
Gate Charge Waveform



Unclamped Inductive Switching Test Circuit

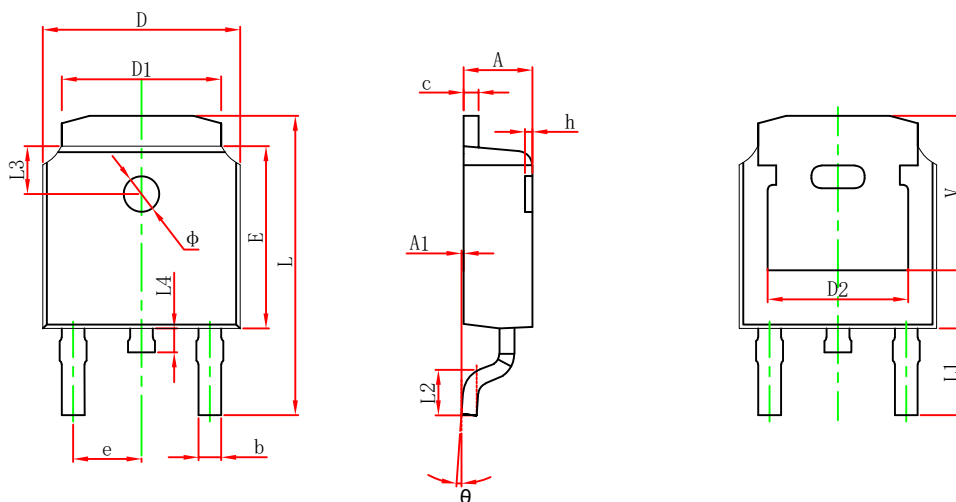
Unclamped Inductive Switching Waveforms

Peak Diode Recovery dv/dt Test Circuit & Waveform



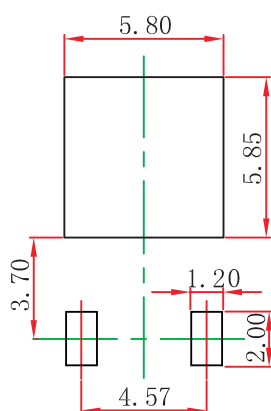
Peak Diode Recovery dv/dt Waveforms

Package Dimension



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.700	0.860	0.025	0.030
c	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	4.830 REF.		0.190 REF.	
E	6.000	6.300	0.236	0.244
e	2.186	2.386	0.086	0.094
L	9.712	10.312	0.382	0.406
L1	2.900 REF.		0.114 REF.	
L2	1.400	1.700	0.055	0.067
L3	1.600 REF.		0.063 REF.	
L4	0.600	1.000	0.024	0.039
Φ	1.100	1.300	0.043	0.051
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.250 REF.		0.207 REF.	

TO-252-2L Suggest Pad Layout



NOTE:

1. Controlling dimension: in millimeters.
2. General tolerance: ±0.05mm.
3. The pad layout is for reference purposes only.